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**1 Streamlining life cycle analysis: a method**

Mueller, K.G.; Besant, C.B.;

Environmentally Conscious Design and Inverse Manufacturing, 1999. Proceed EcoDesign '99: First International Symposium On , 1-3 Feb. 1999

Pages:114 - 119

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IEEE CNF

**2 Life cycle inventory of PVC: manufacturing and fabrication processes**

Brinkley, A.; Kirby, J.R.; Wadehra, I.L.; Besnainou, J.; Coulon, R.; Goybet, S. Electronics and the Environment, 1996. ISEE-1996., Proceedings of the 1996 International Symposium on , 6-8 May 1996

Pages:94 - 101

[\[Abstract\]](#)

[\[PDF Full-Text \(556 KB\)\]](#)

IEEE CNF

**3 Life-cycle design system for machined parts - linkage of LCI data to CAD/CAM data**

Nawata, S.; Aoyama, T.;

Environmentally Conscious Design and Inverse Manufacturing, 2001. Proceed EcoDesign 2001: Second International Symposium on , 11-15 Dec. 2001

Pages:299 - 302

[\[Abstract\]](#)

[\[PDF Full-Text \(455 KB\)\]](#)

IEEE CNF

**4 LCA for electronic products. A case study for CD-ROM drives**

Satake, K.; Oishi, S.;

Electronics and the Environment, 1998. ISEE-1998. Proceedings of the 1998 International Symposium on , 4-6 May 1998

Pages:176 - 179

[\[Abstract\]](#)   [\[PDF Full-Text \(336 KB\)\]](#)   IEEE CNF

---

**5 Electronic part life cycle concepts and obsolescence forecasting**

*Solomon, R.; Sandborn, P.A.; Pecht, M.G.;*

Components and Packaging Technologies, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part A: Packaging Technologies, IEEE Transactions on] , Volume: 23 , Issue: 4 , Dec. 2000  
Pages:707 - 717

[\[Abstract\]](#)   [\[PDF Full-Text \(196 KB\)\]](#)   IEEE JNL

---

**6 New materials and process developments for preventative maintenance and repair in cement plants**

*Heath, G.R.; Skora, J.;*

Cement Industry Technical Conference, 1998. 40th Conference Record. 1998  
IEEE/PCA , 17-21 May 1998  
Pages:359 - 365

[\[Abstract\]](#)   [\[PDF Full-Text \(944 KB\)\]](#)   IEEE CNF

---

**7 An Inventory of Intrinsic Sources of Chance Failures in Electronic Packages**

*Connor, J.;*

Component Parts, IEEE Transactions on , Volume: 11 , Issue: 2 , Jun 1964  
Pages:238 - 250

[\[Abstract\]](#)   [\[PDF Full-Text \(1616 KB\)\]](#)   IEEE JNL

---

**8 Approaches to reduce impact of electronic component obsolescence  
Component Information Management System**

*Pertowski, T.; Denham, C.;*

Frequency Control Symposium, 1998. Proceedings of the 1998 IEEE  
International , 27-29 May 1998  
Pages:430 - 438

[\[Abstract\]](#)   [\[PDF Full-Text \(796 KB\)\]](#)   IEEE CNF

---

**9 New metrics and scheduling rules for disassembly and bulk recycling**

*Stuart, J.A.; Christina, V.;*

Electronics Packaging Manufacturing, IEEE Transactions on [see also Components, Packaging and Manufacturing Technology, Part C: Manufacturing Technology, IEEE Transactions on] , Volume: 26 , Issue: 2 , April 2003  
Pages:133 - 140

[\[Abstract\]](#)   [\[PDF Full-Text \(502 KB\)\]](#)   IEEE JNL

---

**10 A new reliability test for multilayer ceramic capacitors**

*Ingalls, M.W.;*

Components, Packaging, and Manufacturing Technology, Part A, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on] , Volume: 17 , Issue: 3 , Sept. 1994  
Pages:344 - 347

[\[Abstract\]](#)   [\[PDF Full-Text \(316 KB\)\]](#)   IEEE JNL

---

**11 Keeping pace with technological advances when funding resources diminished [military systems]**

*Schafer, D.L.;*

AUTOTESTCON 2003. IEEE Systems Readiness Technology Conference.

Proceedings , 22-25 Sept. 2003

Pages:584 - 587

[\[Abstract\]](#)   [\[PDF Full-Text \(402 KB\)\]](#)   IEEE CNF

---

**12 A framework for structured data retrieval in LCA using feature technology**

*Otto, H.E.; Mueller, K.G.; Kimura, F.;*

Environmentally Conscious Design and Inverse Manufacturing, 2001. Proceed

EcoDesign 2001: Second International Symposium on , 11-15 Dec. 2001

Pages:250 - 255

[\[Abstract\]](#)   [\[PDF Full-Text \(588 KB\)\]](#)   IEEE CNF

---

**13 Design for environment development at Motorola**

*Hoffman, W.F., III; Locascio, A.;*

Electronics and the Environment, 1997. ISEE-1997., Proceedings of the 1997

International Symposium on , 5-7 May 1997

Pages:210 - 214

[\[Abstract\]](#)   [\[PDF Full-Text \(612 KB\)\]](#)   IEEE CNF

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